

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination NAKANO, TAKAHIKO	
		Examiner	Art Unit	Page 1 of 1
		Sang Nguyen	2877	

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-6,741,363	05-2004	Kaupert, Bertram	356/602
B	US-6,492,652	12-2002	Muller, Daniel	250/559.38
C	US-6,122,039	09-2000	Schumacher, Neal A.	356/3.07
D	US-5,519,204	05-1996	Rudd et al.	250/205
E	US-5,218,427	06-1993	Koch, Stephen K.	356/602
F	US-5,113,080	05-1992	Leu et al.	250/559.31
G	US-5,065,526	11-1991	Breyer, Karl-Hermann	33/702
H	US-4,970,384	11-1990	Kambe et al.	250/221
I	US-4,897,536	01-1990	Miyoshi, Takashi	250/201.6
J	US-4,864,147	09-1989	Ikari et al.	250/559.22
K	US-4,464,038	08-1984	Nanba, Yasuhiro	396/106
L	US-3,740,563	06-1973	Reichard, Thomas E.	117/15
M	US-3,520,607	07-1970	ZOOT ROBERT M	356/4.05

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
U				
V				
W				
X				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.